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L1	8977	709/213.ccls. or 709/216.ccls. or 709/253.ccls. or 709/230.ccls. or 709/245.ccls. or 709/224-225.ccls. or 709/239.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/09 09:28
L2	105	((bus or network\$3) with (bandwidth or usage or utilization)) same (snoop\$3 or broadcast\$3 or multicast\$3) same director\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/09 09:32
L3	35	select\$4 same((bus or network\$3) with (bandwidth or usage or utilization)) same (snoop\$3 or broadcast\$3 or multicast\$3) same director\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/09 09:33
L4	3	1 and 3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/09 09:33
L5	27	3 and (@ad<="20010314" or @rlad<="20010314")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/09 09:39
L6	7559	cache with (coheren\$3 or consisten\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/09 09:40
L7	8	5 and 6	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/09 09:40

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